



Contactless Bulk Resistivity/Sheet Resistance Model 1510 Standalone

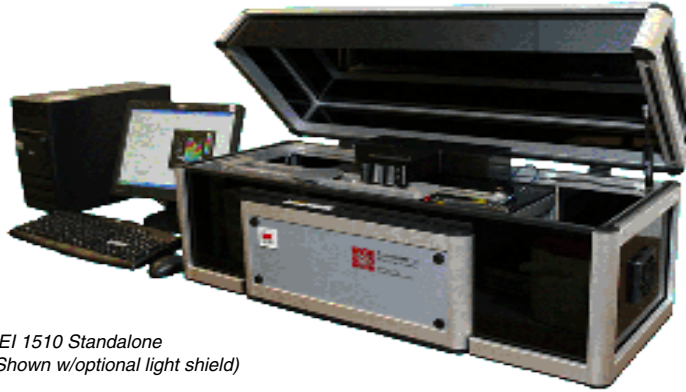
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Model 1510



Measurement and Mapping Systems



LEI 1510 Standalone
(Shown w/optional light shield)

Characterization of:

- All compound semiconductor materials (epi, annealed ion-implants on semi insulating and some doped substrates)
- Silicon wafers (bulk Si, epi, annealed ion-implants, and POCl₃ doping uniformity on high resistivity substrates)
- Thin film metallization (contact factory for details)

Measurement Capabilities

- Normal coil gap ($\geq .035$ "/.889mm)
- Wafer sizes 2" (50mm) to 8" (200mm) wafers
- Manual loading

Sensor Transducer Sizes

- 14 mm diameter for all ranges

Operating Characteristics

- High spatial resolution
- Precise voltage regulation for tight linearity and consistently repeatable results

Sample Handling and Sensing

- Up to 300 measurement points
- Automatic drift compensation
- Software-selectable resistivity ranges

Accessories and Options

- Capacitance thickness capability
- Light shield

Specifications		
Range	Sheet Resistance	Bulk Resistivity
HI	15 - 3,000 ohms/sq	1.0 - 200 ohms-cm
LO	0.2 - 15.0 ohms/sq	0.01 - 1.0 ohms-cm
XL	0.1 - 1.5 ohms/sq	0.005 - 0.1 ohms-cm

* Standard Deviation
0.1% to 1.0% - Depends on the range

* Linearity
0.035 to 3,000 ohms/sq \pm 3%

* Specifications based on current NIST standards.
Actual performance may exceed this depending on application.